



Description

The XPX30L60RD uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

$V_{DS} = -30V, I_D = -60A$

$R_{DS(ON)} = 9.0m\Omega @ V_{GS} = -10V$

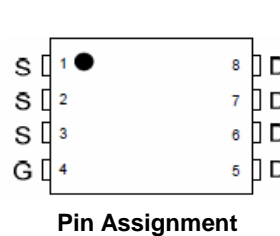
$R_{DS(ON)} = 14m\Omega @ V_{GS} = -4.5V$

General Features

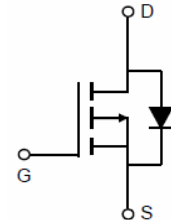
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

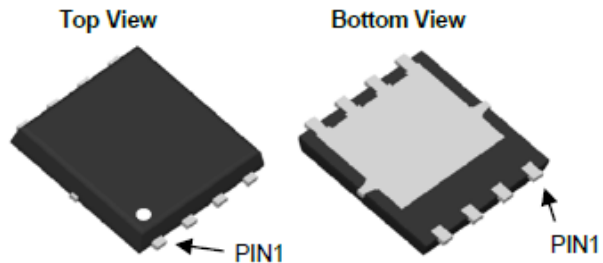
- Load switch
- Battery protection



Pin Assignment



Schematic diagram



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|------------|---------------------|----------|
| XPX30L60RD | PDFN5*6-8L | XPX30L60RD XXX YYYY | 5000 |

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|---------------------------|---|------------|--------------|
| V_{DS} | Drain-Source Voltage | -30 | V |
| V_{GS} | Gate-Source Voltage | ± 25 | V |
| $I_D @ T_C = 25^\circ C$ | Continuous Drain Current, $V_{GS} @ -10V^1$ | -60 | A |
| $I_D @ T_C = 100^\circ C$ | Continuous Drain Current, $V_{GS} @ -10V^1$ | -38 | A |
| $I_D @ T_A = 25^\circ C$ | Continuous Drain Current, $V_{GS} @ -10V^1$ | -11 | A |
| $I_D @ T_A = 70^\circ C$ | Continuous Drain Current, $V_{GS} @ -10V^1$ | -8.9 | A |
| I_{DM} | Pulsed Drain Current ² | -150 | A |
| EAS | Single Pulse Avalanche Energy ³ | 125 | mJ |
| I_{AS} | Avalanche Current | -50 | A |
| $P_D @ T_C = 25^\circ C$ | Total Power Dissipation ⁴ | 45 | W |
| $P_D @ T_A = 25^\circ C$ | Total Power Dissipation ⁴ | 2.3 | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | $^\circ C$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | $^\circ C$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ | 62 | $^\circ C/W$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ ($t \leq 10s$) | 28 | $^\circ C/W$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | 2.9 | $^\circ C/W$ |

Electrical Characteristics (T_c=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|------------------------|--|--|------|---------|------|-------|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =-250uA | -30 | -33 | --- | V |
| ΔBVDSS/ΔT _J | BVDSS Temperature Coefficient | Reference to 25°C, I _D =-1mA | --- | -0.0232 | --- | V/°C |
| RDS(ON) | Static Drain-Source On-Resistance ² | V _{GS} =-10V, I _D =-15A | --- | 9 | 13 | mΩ |
| | | V _{GS} =-4.5V, I _D =-10A | --- | 14 | 20 | |
| VGS(th) | Gate Threshold Voltage | V _{GS} =V _{DS} , I _D =-250uA | -1.0 | -1.7 | -2.5 | V |
| ΔVGS(th) | V _{GS(th)} Temperature Coefficient | | --- | 4.6 | --- | mV/°C |
| IDSS | Drain-Source Leakage Current | V _{DS} =-24V, V _{GS} =0V, T _J =25°C | --- | --- | -1 | uA |
| | | V _{DS} =-24V, V _{GS} =0V, T _J =55°C | --- | --- | -5 | |
| IGSS | Gate-Source Leakage Current | V _{GS} =±25V, V _{DS} =0V | --- | --- | ±100 | nA |
| gfs | Forward Transconductance | V _{DS} =-5V, I _D =-30A | --- | 30 | --- | S |
| R _g | Gate Resistance | V _{DS} =0V, V _{GS} =0V, f=1MHz | --- | 9 | --- | Ω |
| Q _g | Total Gate Charge (-4.5V) | V _{DS} =-15V, V _{GS} =-4.5V, I _D =-15A | --- | 22 | --- | nC |
| Q _{gs} | Gate-Source Charge | | --- | 8.7 | --- | |
| Q _{gd} | Gate-Drain Charge | | --- | 7.2 | --- | |
| Td(on) | Turn-On Delay Time | V _{DD} =-15V, V _{GS} =-10V, R _G =3.3Ω I _D =-15A | --- | 8 | --- | ns |
| T _r | Rise Time | | --- | 73.7 | --- | |
| Td(off) | Turn-Off Delay Time | | --- | 61.8 | --- | |
| T _f | Fall Time | | --- | 24.4 | --- | |
| Ciss | Input Capacitance | V _{DS} =-15V, V _{GS} =0V, f=1MHz | --- | 2148 | --- | pF |
| Coss | Output Capacitance | | --- | 312 | --- | |
| Crss | Reverse Transfer Capacitance | | --- | 242 | --- | |
| IS | Continuous Source Current ^{1,5} | V _G =V _D =0V, Force Current | --- | --- | -45 | A |
| ISM | Pulsed Source Current ^{2,5} | | --- | --- | -150 | A |
| VSD | Diode Forward Voltage ² | V _{GS} =0V, I _S =-1A, T _J =25°C | --- | --- | -1 | V |
| trr | Reverse Recovery Time | IF=-15A, dI/dt=100A/μs, T _J =25°C | --- | 19 | --- | nS |
| Q _{rr} | Reverse Recovery Charge | | --- | 9 | --- | nC |

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2.The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%
- 3.The EAS data shows Max. rating. The test condition is V_{DD}=-25V, V_{GS}=-10V, L=0.1mH, I_{AS}=-50A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation.

Typical Characteristics

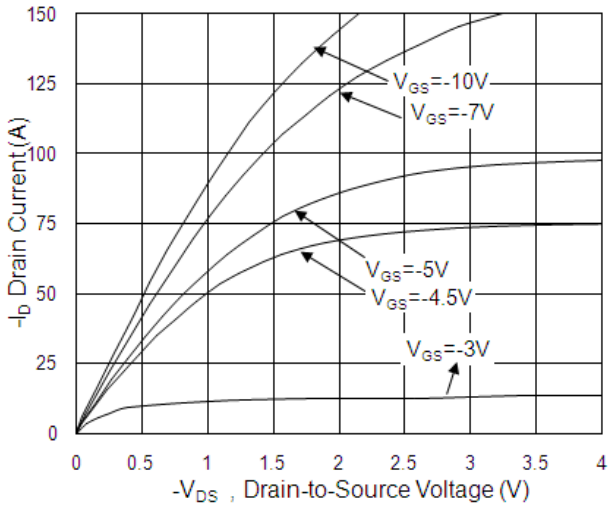


Fig.1 Typical Output Characteristics

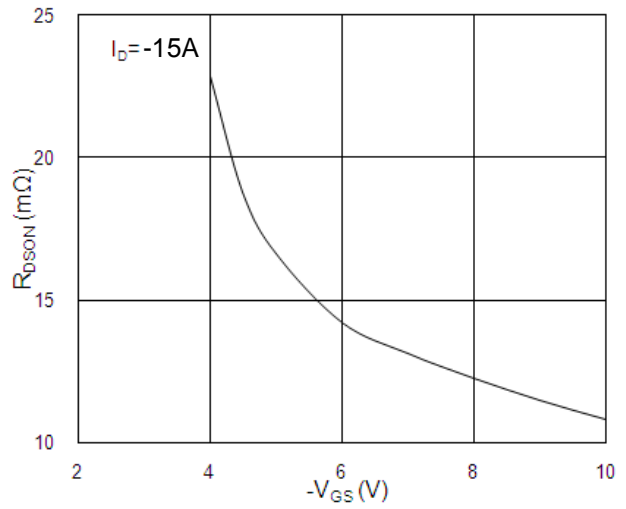


Fig.2 On-Resistance vs. G-S Voltage

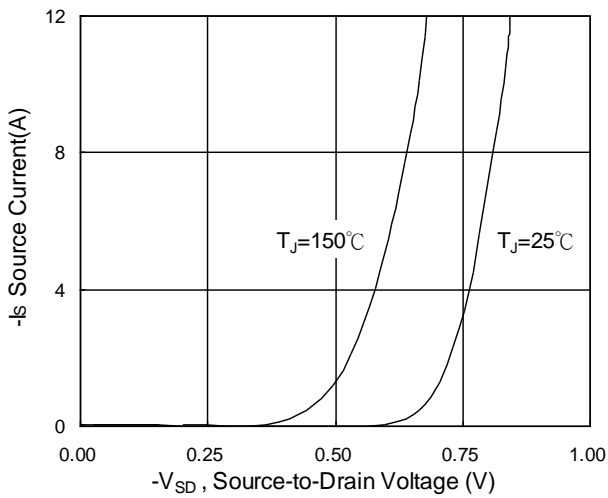


Fig.3 Forward Characteristics of Reverse

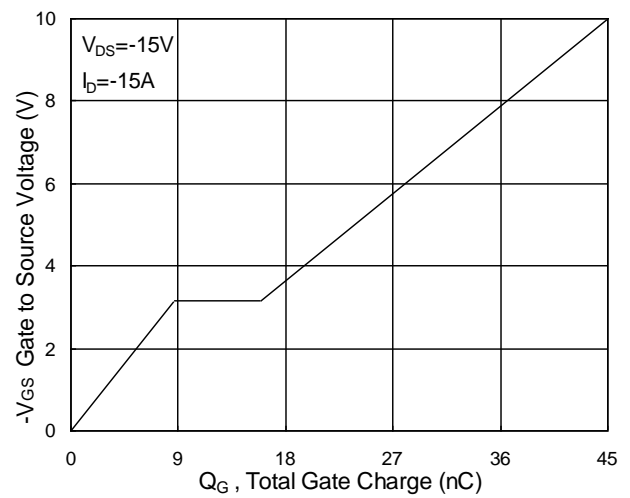


Fig.4 Gate-charge Characteristics

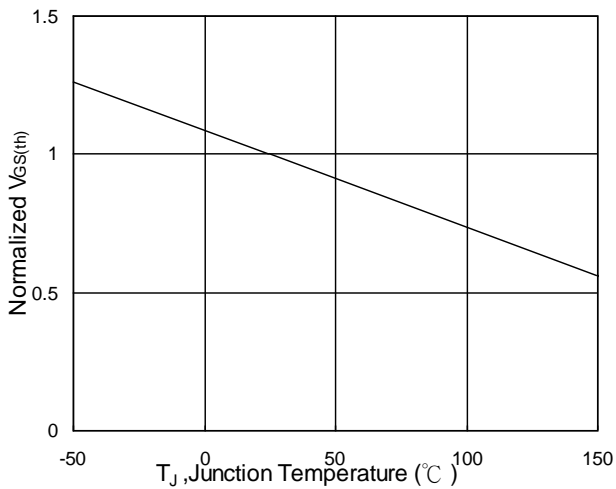


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

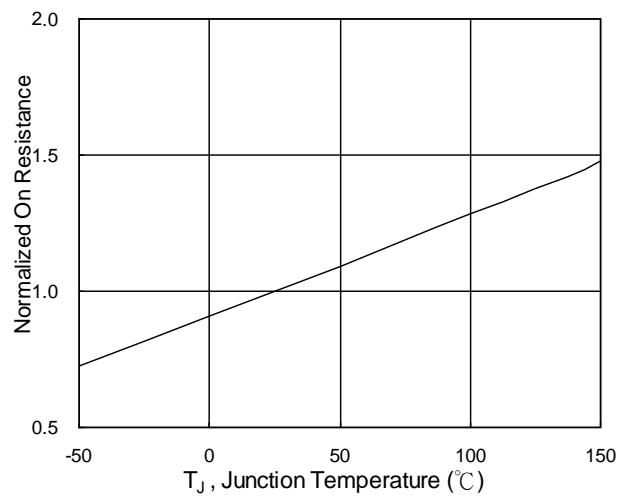


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

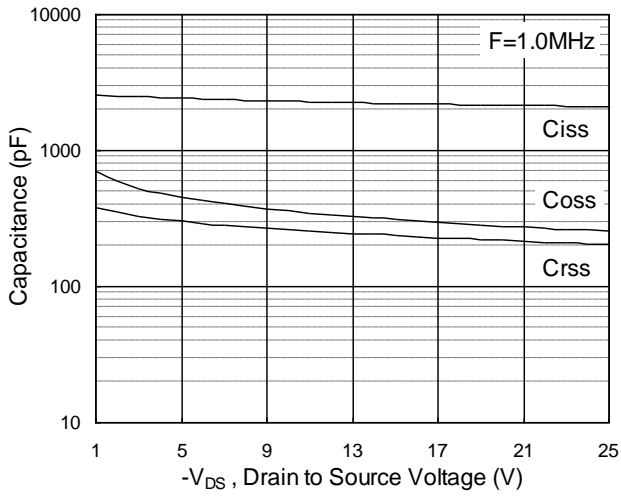


Fig.7 Capacitance

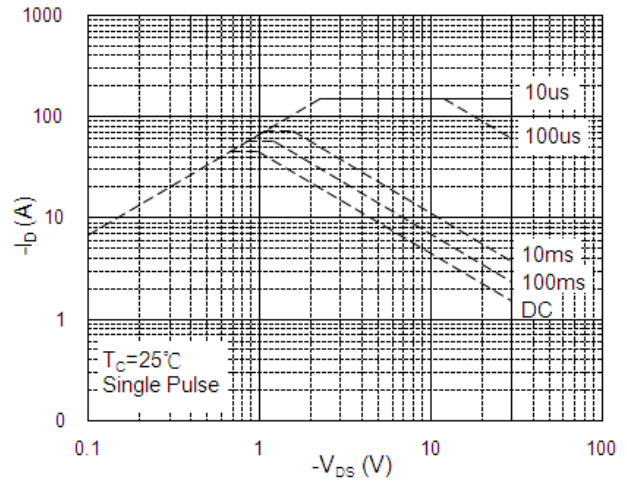


Fig.8 Safe Operating Area

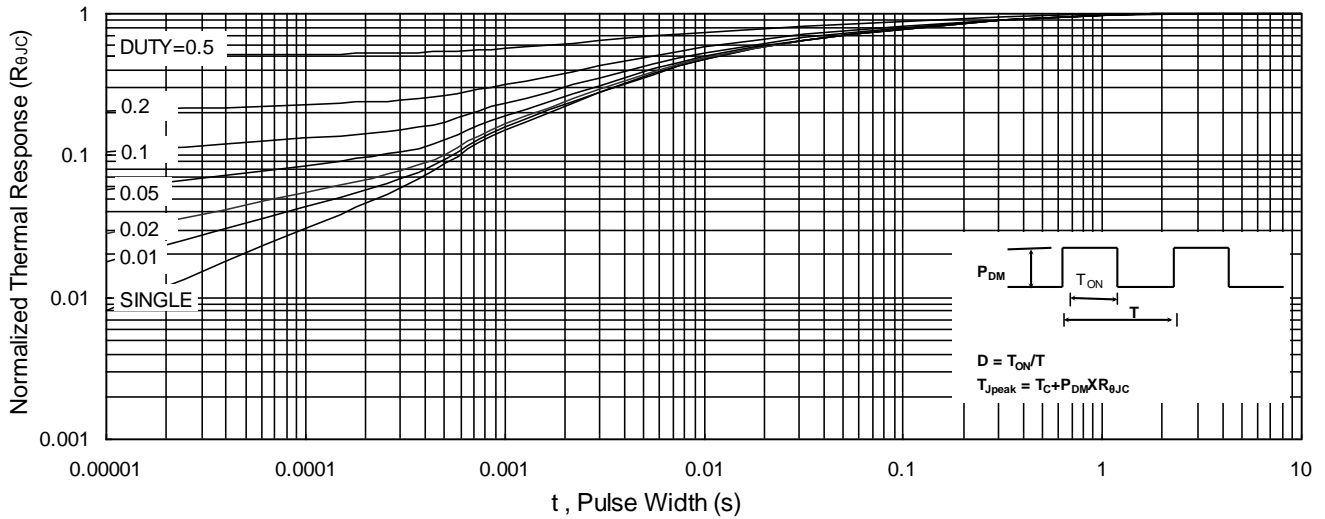


Fig.9 Normalized Maximum Transient Thermal Impedance

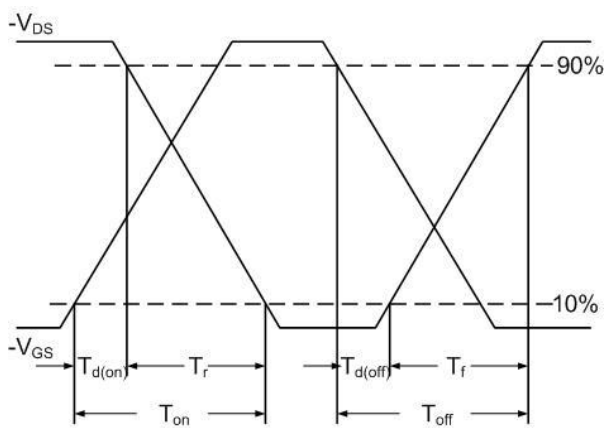


Fig.10 Switching Time Waveform

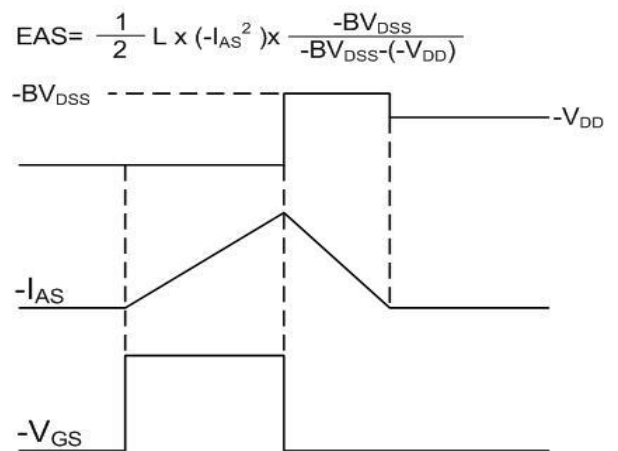
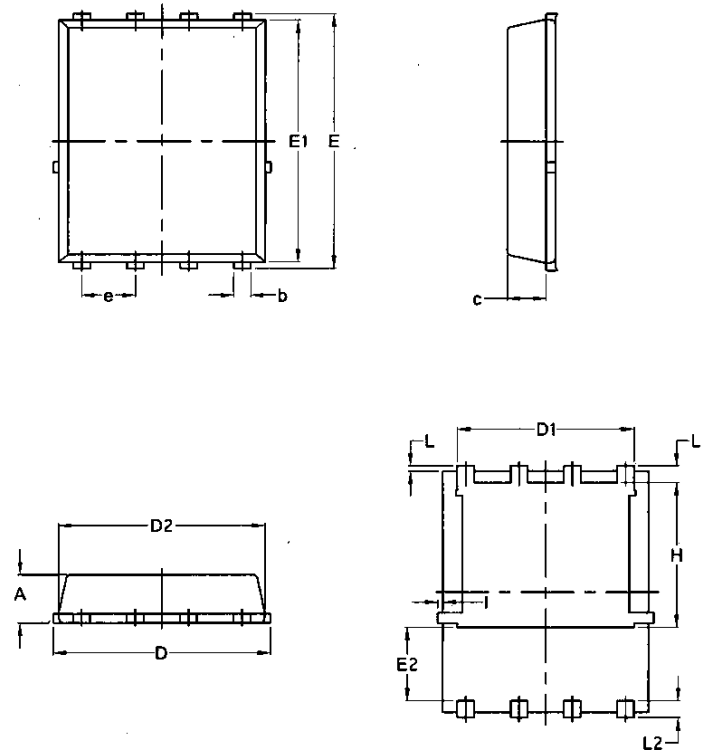


Fig.11 Unclamped Inductive Switching Waveform

Package Mechanical Data-DFN5*6-8L-JQ Single


| Symbol | Common | | | |
|--------|----------|--------|----------|--------|
| | mm | | Inch | |
| | Min | Max | Min | Max |
| A | 1.03 | 1.17 | 0.0406 | 0.0461 |
| b | 0.34 | 0.48 | 0.0134 | 0.0189 |
| c | 0.824 | 0.0970 | 0.0324 | 0.082 |
| D | 4.80 | 5.40 | 0.1890 | 0.2126 |
| D1 | 4.11 | 4.31 | 0.1618 | 0.1697 |
| D2 | 4.80 | 5.00 | 0.1890 | 0.1969 |
| E | 5.95 | 6.15 | 0.2343 | 0.2421 |
| E1 | 5.65 | 5.85 | 0.2224 | 0.2303 |
| E2 | 1.60 | / | 0.0630 | / |
| e | 1.27 BSC | | 0.05 BSC | |
| L | 0.05 | 0.25 | 0.0020 | 0.0098 |
| L1 | 0.38 | 0.50 | 0.0150 | 0.0197 |
| L2 | 0.38 | 0.50 | 0.0150 | 0.0197 |
| H | 3.30 | 3.50 | 0.1299 | 0.1378 |
| I | / | 0.18 | / | 0.0070 |

Flow (wave) soldering (solder dipping)

| Product | Peak Temperature | Dipping Time |
|----------------|------------------|--------------|
| Pb device | 245°C ±5°C | 5sec±1sec |
| Pb-Free device | 260°C +0/-5°C | 5sec±1sec |



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

Attention:

- Any and all XPX power products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your XPX power representative nearest you before using any XPX power products described or contained herein in such applications.
- XPX power assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all XPX power products described or contained herein.
- Specifications of any and all XPX power products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- XPX power Semiconductor CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all XPX power products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of XPX power Semiconductor CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. XPX power believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/ technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the XPX power product that you intend to use.
- This catalog provides information as of Sep.2019. Specifications and information herein are subject to change without notice.